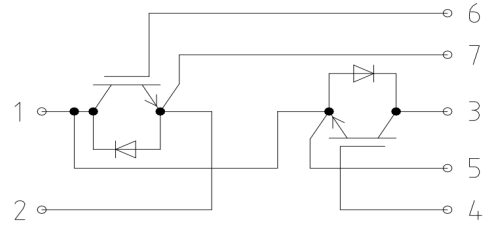


PRODUCT FEATURES

- IGBT CHIP(Trench+FS)
- Low saturation voltage and positive temperature coefficient
- Fast switching and short tail current
- Free wheeling diodes with fast and soft reverse recovery
- Temperature sense included
- High short circuit capability


APPLICATIONS

- High frequency switching application
- Medical applications
- Motion/servo control
- UPS systems


IGBT

 ABSOLUTE MAXIMUM RATINGS($T_C = 25^\circ\text{C}$ unless otherwise specified)

Symbol	Parameter/ Test Conditions	Values	Unit
V_{CES}	Collector Emitter Voltage	1200	V
V_{GES}	Gate Emitter Voltage	± 20	
I_c	DC Collector Current	$T_C = 25^\circ\text{C}, T_{Jmax} = 175^\circ\text{C}$	362
		$T_C = 100^\circ\text{C}, T_{Jmax} = 175^\circ\text{C}$	200
I_{CM}	Repetitive Peak Collector Current	$t_p = 1\text{ms}$	400
P_{tot}	Power Dissipation Per IGBT	$T_C = 25^\circ\text{C}, T_{Jmax} = 175^\circ\text{C}$	1.1

Diode

 ABSOLUTE MAXIMUM RATINGS($T_C = 25^\circ\text{C}$ unless otherwise specified)

Symbol	Parameter/ Test Conditions	Values	Unit
V_{RRM}	Repetitive Reverse Voltage	1200	V
$I_{F(AV)}$	Average Forward Current	200	A
I_{FRM}	Repetitive Peak Forward Current	$t_p = 1\text{ms}$	
I^2t		$T_J = 150^\circ\text{C}, t = 10\text{ms}, V_R = 0\text{V}$	12

MODULE CHARACTERISTICS($T_C = 25^\circ\text{C}$ unless otherwise specified)

Symbol	Parameter/ Test Conditions	Values	Unit	
T_{Jmax}	Max. Junction Temperature	175	$^\circ\text{C}$	
T_{Jop}	Operating Temperature	-40~150		
T_{stg}	Storage Temperature	-40~125		
V_{isol}	Isolation Breakdown Voltage	AC, 50Hz(R.M.S), $t = 1\text{minute}$	3000	V
CTI	Comparative Tracking Index		>200	
Torque	to heatsink	Recommended (M6)	3~5	Nm
	to terminal	Recommended (M6)	3~5	Nm
Weight			320	g

IGBT

 ELECTRICAL CHARACTERISTICS ($T_C = 25^\circ\text{C}$ unless otherwise specified)

Symbol	Parameter/ Test Conditions		Min.	Typ.	Max.	Unit
$V_{GE(th)}$	Gate Emitter Threshold Voltage	$V_{CE}=V_{GE}, I_C=6\text{mA}$	5.5	6.0	6.5	V
$V_{CE(sat)}$	Collector Emitter Saturation Voltage	$I_C=200\text{A}, V_{GE}=15\text{V}, T_J=25^\circ\text{C}$		1.70	2.05	
		$I_C=200\text{A}, V_{GE}=15\text{V}, T_J=125^\circ\text{C}$		2.15		
		$I_C=200\text{A}, V_{GE}=15\text{V}, T_J=150^\circ\text{C}$		2.25		
I_{CES}	Collector Leakage Current	$V_{CE}=1200\text{V}, V_{GE}=0\text{V}, T_J=25^\circ\text{C}$			1	mA
		$V_{CE}=1200\text{V}, V_{GE}=0\text{V}, T_J=150^\circ\text{C}$			10	mA
I_{GES}	Gate Leakage Current	$V_{CE}=0\text{V}, V_{GE}=\pm 20\text{V}, T_J=25^\circ\text{C}$			± 500	nA
R_{gint}	Integrated Gate Resistor			2		Ω
Q_g	Gate Charge	$V_{CE}=600\text{V}, I_C=200\text{A}, V_{GE}=15\text{V}$		2.3		μC
C_{ies}	Input Capacitance	$V_{CE}=25\text{V}, V_{GE}=0\text{V}, f=1\text{MHz}$		30.5		nF
C_{res}	Reverse Transfer Capacitance				1.35	
$t_{d(on)}$	Turn on Delay Time	$V_{CC}=600\text{V}, I_C=200\text{A}$ $R_G=1.5\Omega,$ $V_{GE}=\pm 15\text{V},$ Inductive Load	$T_J=25^\circ\text{C}$		90	ns
			$T_J=150^\circ\text{C}$		110	ns
t_r	Rise Time		$T_J=25^\circ\text{C}$		70	ns
			$T_J=150^\circ\text{C}$		80	ns
$t_{d(off)}$	Turn off Delay Time	$T_J=25^\circ\text{C}$		520	ns	
		$T_J=150^\circ\text{C}$		570	ns	
t_f	Fall Time	$T_J=25^\circ\text{C}$		120	ns	
		$T_J=150^\circ\text{C}$		225	ns	
E_{on}	Turn on Energy	$T_J=25^\circ\text{C}$		25	mJ	
		$T_J=150^\circ\text{C}$		40	mJ	
E_{off}	Turn off Energy	$T_J=25^\circ\text{C}$		28	mJ	
		$T_J=150^\circ\text{C}$		50	mJ	
I_{sc}	Short Circuit Current	$t_{psc} \leq 10\mu\text{s}, V_{GE}=15\text{V}$ $T_J=150^\circ\text{C}, V_{CC}=800\text{V}$		1100		A
R_{thJC}	Junction to Case Thermal Resistance (Per IGBT)				0.076	K /W

Diode-inverter

ELECTRICAL CHARACTERISTICS (T_C =25°C unless otherwise specified)

Symbol	Parameter/ Test Conditions	Min.	Typ.	Max.	Unit	
V _F	Collector Emitter Voltage	I _F =200A, V _{GE} =0V, T _J = 2 5 °C		1.7	2.3	V
		I _F =200A, V _{GE} =0V, T _J = 1 2 5 °C		1.5		
		I _F =200A, V _{GE} =0V, T _J = 1 5 0 °C		1.45		
T _{rr}	Gate Emitter Voltage		575		nS	
I _{RRM}	DC Collector Current	I _F =200A , V _R =600V di _F /dt=-3100A/μs T _J =150°C	200		A	
Q _{RR}	Repetitive Peak Collector Current		47		μC	
E _{rec}	Power Dissipation Per IGBT		17		mJ	
R _{thJCD}	Junctionto CaseThermal Resistance (Per Diode)				0.2	kW

IGBT Typical Performance

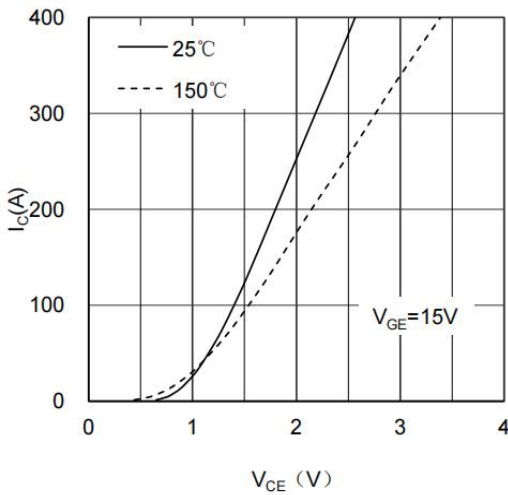


Figure1 Typical IGBT output characteristics

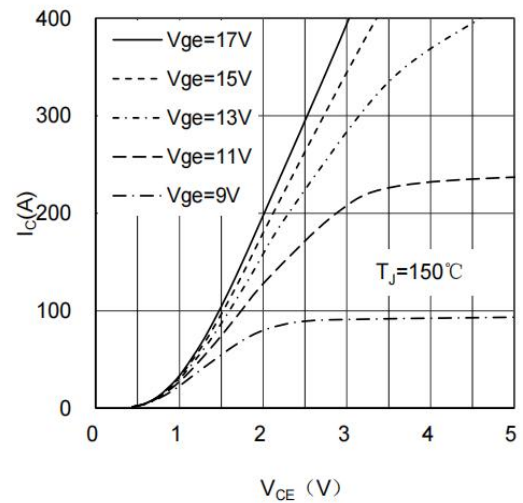


Figure2 Typical IGBT output characteristics

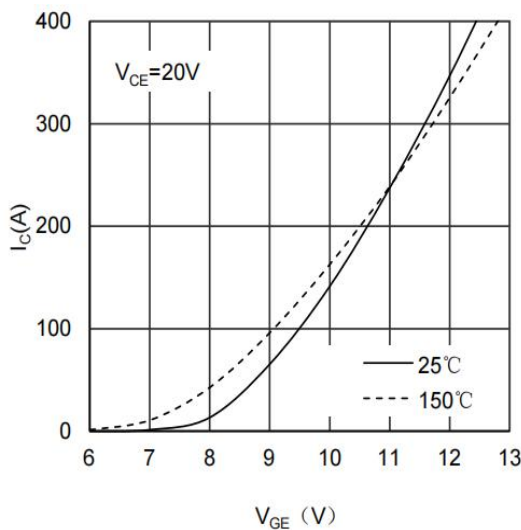


Figure3 Typical IGBT transfer characteristics

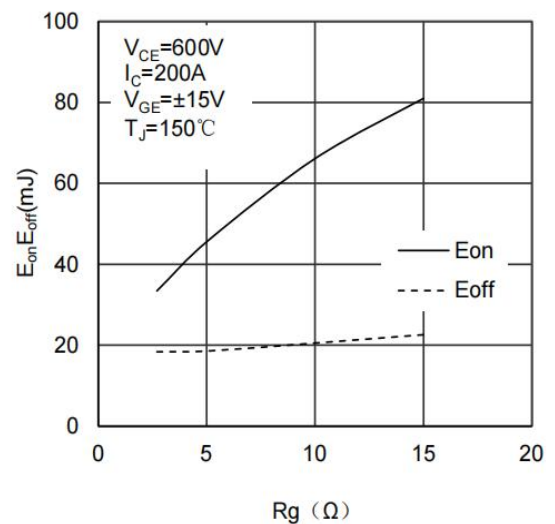


Figure4 Switching Energy vs Gate Resistor IGBT

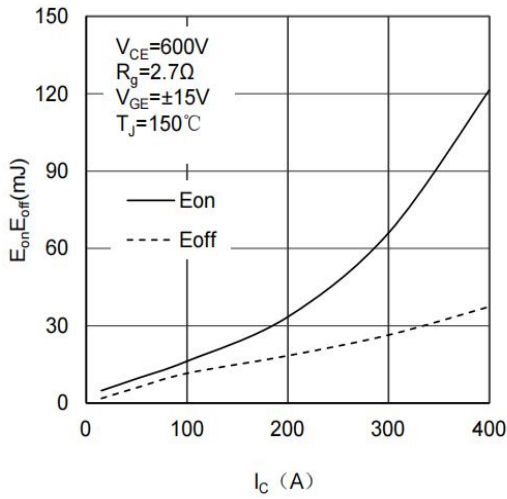


Figure5 Switching Energy vs Collector Current IGBT

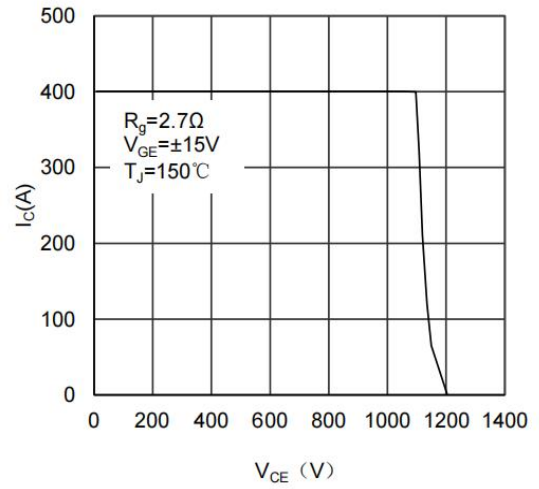


Figure6 Reverse Biased Safe Operating Area IGBT

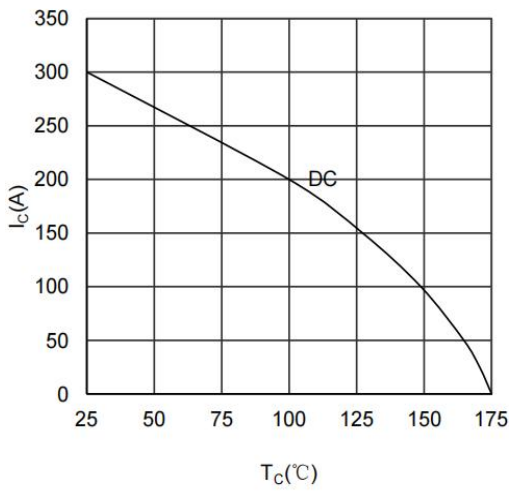


Figure7 Collector Current vs Case temperature IGBT

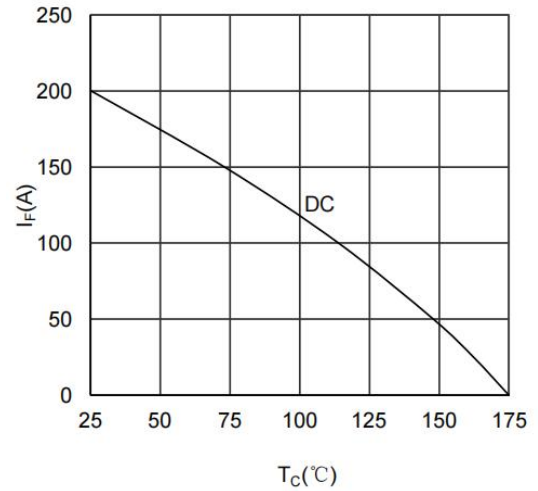


Figure8 Forward current vs Case temperature Diode

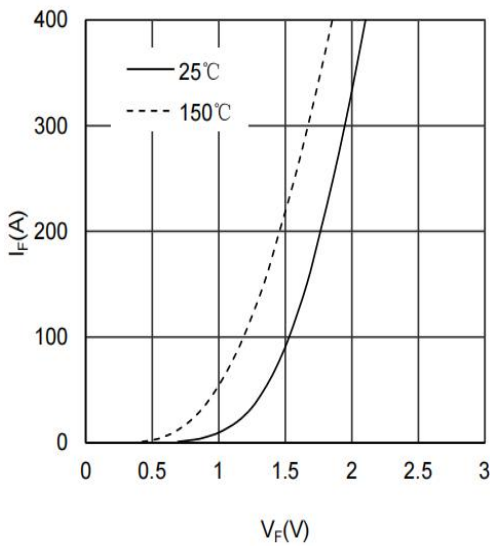


Figure9 Diode Forward Characteristics Diode

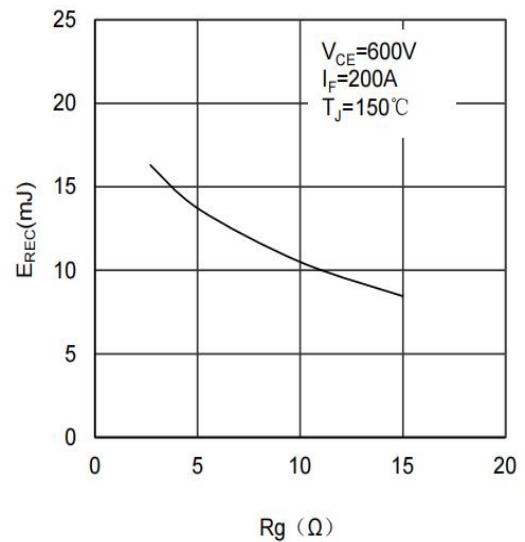


Figure10 Switching Energy vs Gate Resistor Diode

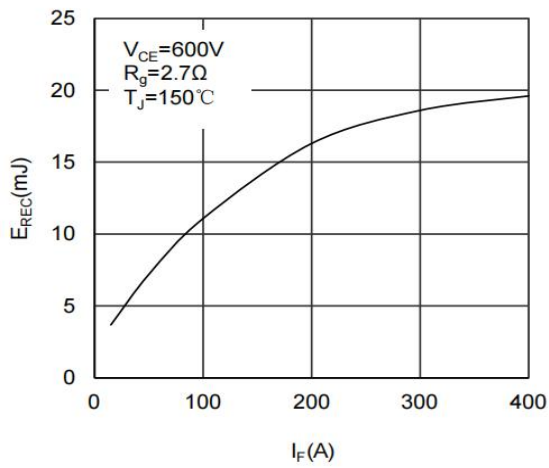


Figure11 Switching Energy vs Forward Current Diode

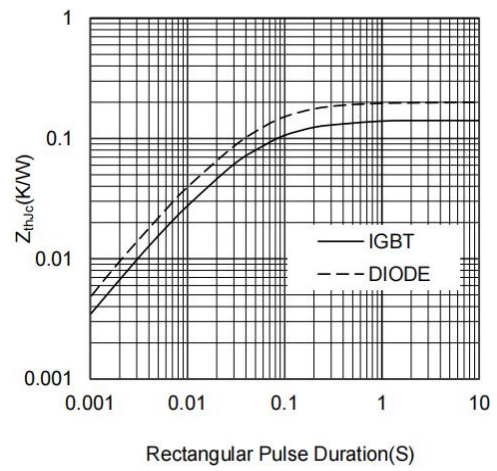
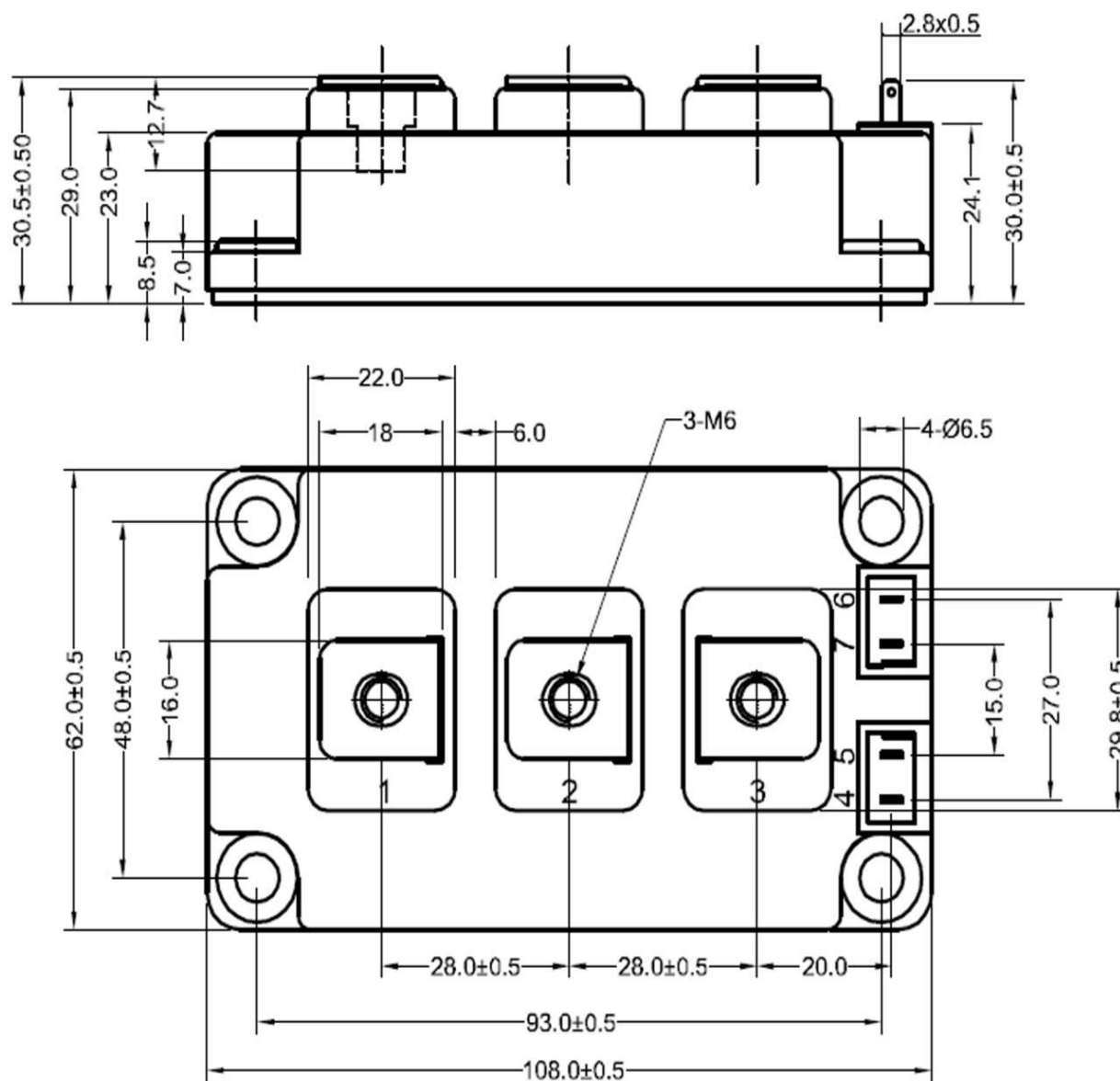


Figure12 Transient Thermal Impedance of Diode and IGBT

Package Dimensions: 62MM



Dimensions in (mm)
Figure 13 Package Outline

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